



11760

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Yuji IMAI

Group Art Unit: 2851

Application No.: 10/791,810

Examiner: H. Nguyen

Filed: March 4, 2004

Docket No.: 109325.01

For: METHOD FOR EVALUATING LITHOGRAPHY SYSTEM, METHOD FOR ADJUSTING SUBSTRATE-PROCESSING APPARATUS, LITHOGRAPHY SYSTEM, AND EXPOSURE APPARATUS

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

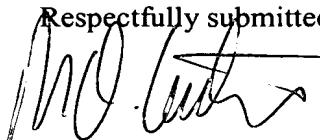
Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the reference(s) listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the reference(s) be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

1. This Information Disclosure Statement is being filed more than three months after the U.S. filing date and after the mailing date of a Final Rejection, Notice of Allowance, or other action that closes prosecution (e.g., Quayle Action), but before payment of the Issue Fee. Attached is our Check No. 161179 in the amount of \$180.00 in payment of the fee under 37 CFR §1.17(p). Please credit or debit Deposit Account No. 15-0461 as needed to ensure consideration of the disclosed information. Two duplicate copies of this paper are attached.

a. I hereby certify that each item of information contained in this Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Information Disclosure Statement.  
37 CFR §1.97(e)(1).

2. Each item of information contained in this Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart application, and this communication was not received by any individual designated in §1.56(c) more than thirty days prior to the filing of this Information Disclosure Statement.

- 3. The reference(s) was/were cited in a counterpart foreign application. An English language version of the foreign search report is attached for the Examiner's information.
- 4. In accordance with 37 CFR §1.98(a)(2)(i), copies of any U.S. patents and patent application publications are not attached.

Respectfully submitted,  
  
Mario A. Costantino  
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MAC/ccs

Date: December 1, 2004

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<b>DEPOSIT ACCOUNT USE AUTHORIZATION</b> Please grant any extension necessary for entry; Charge any fee due to our Deposit Account No. 15-0461
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Sheet 1 of 1

Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE	ATTY DOCKET NO. 109325.01	APPLICATION NO. 10/791,810		
INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)						
		APPLICANT(S) Yuji IMAI				
		FILING DATE March 4, 2004	GROUP 2851			
U.S. PATENT DOCUMENTS						
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
		4,908,656	03-13-1990	Suwa et al.		
		5,815,594	09-29-1998	Tanaka		
		5,252,414	10-12-1993	Yamashita et al.		
FOREIGN PATENT DOCUMENTS						
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)						
		SPIE Vol. 1464 Integrated Circuit Metrology, Inspection, and Process Control V (1991), "Use of diffracted light from latent images to improve lithography control", K.C. Hickman et al., pages 245-257.				
EXAMINER					DATE CONSIDERED	
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.						